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|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/820,535 | | Applicant(s)/Patent Under Reexamination ASLAN ET AL. | |
| | Examiner Gail Verbitsky | | Art Unit 2859 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| * | A | US-6,733,174 | 05-2004 | Matsumoto et al. | 374/178 |
| * | B | US-6,242,974 | 06-2001 | Kunst, David J. | 330/9 |
| * | C | US-2005/0220171 | 10-2005 | Faour et al. | 374/178 |
| * | D | US-5,546,041 | 08-1996 | Szajda, Kenneth S. | 327/512 |
| * | E | US-3,812,717 | 05-1974 | Miller et al. | 374/178 |
| * | F | US-6,876,250 | 04-2005 | Hsu et al. | 327/539 |
| * | G | US-7,112,948 | 09-2006 | Daly et al. | 323/316 |
| * | H | US-6,724,234 | 04-2004 | Iliasevitch et al. | 327/378 |
| * | I | US-7,118,273 | 10-2006 | Schnaitter, William N. | 374/168 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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